

IMFEDK 2012 Awards

■ IEEE EDS Kansai Chapter IMFEDK Best Paper Award

Authors: **Hiroki Niwa, Jun Suda and Tsunenobu Kimoto** Paper ID: C-1
Title: “Fundamental Study on Junction Termination Structures for Ultrahigh-Voltage SiC PiN Diodes”
Affiliation: Kyoto University

■ IEEE EDS Kansai Chapter IMFEDK Student Paper Award

Author: **Takamasa Kurumi** Paper ID: PA-02
Title: “TEM observation of directly bonded interface between Si and SiC”
Coauthors: Ryosuke Araki, Hiroyuki Kinoshita and Masahiro Yoshimoto
Affiliation: Kyoto Institute of Technology

Author: **Gota Murai**¹ Paper ID: PA-03
Title: “Photoluminescence study on recrystallization of ultra-shallow junction towards in-line measurements”
Coauthors: Masashi Okutani¹, Hiroki Saikusa¹, Masahiro Yoshimoto¹, Woo Sik Yoo²
Affiliation: ¹Kyoto Institute of Technology, ²WaferMasters, Inc.

Author: **Yasuaki Miyoshi**¹ Paper ID: PB-05
Title: “Numerical simulation of transport properties in InAs/Si heterojunction nanowire tunneling field effect transistors”
Coauthors: Matsuto Ogawa¹, Satofumi Souma¹, Hajime Nakamura²
Affiliation: ¹Kobe University, ²IBM Japan

Author: **Masashi Inoue**¹ Paper ID: PC-01
Title: “Characteristic Shift of a CTFT Inverter using n-type IGZO and p-type F8T2 TFTs after Temperature and Operation Stresses”
Coauthors: Takayuki Hasegawa¹, Takashi Nakanishi¹, Mutsumi Kimura¹, Kenji Nomura², Toshio Kamiya², Hideo Hosono²
Affiliation: ¹Ryukoku University, ²Tokyo Institute of Technology

Author: **Norimitsu Wakama**¹ Paper ID: PC-03
Title: “A polarization analyzing CMOS image sensor with metal wire grid in 65-nm standard CMOS technology”
Coauthors: Hitoshi Matsuoka¹, Keisuke Ando¹, Toshihiko Noda^{1,2}, Kiyotaka Sasagawa^{1,2}, Takashi Tokuda^{1,2}, Jun Ohta^{1,2}
Affiliation: ¹Nara Institute of Science and Technology, ²CREST